Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/774,607	NAKAI, SHINYA	
Examiner	Art Unit	

Tuan A. Tran

2618

SEARCHED					
Class	Subclass	Date	Examiner		
455	78-83	12/18/2007	п		
455	73,550.1				
455	552.1				
455	553.1				
455	575.1,7				
455	90.1-3				
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333	134,175				
370	275,278				
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370	286,297				
370	246,172				
370	185				
257	728,760				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
Interference text search		12/18/2007	π		

SEARCH NOT (INCLUDING SEARCH)_
	DATE	EXMR
EAST (USPAT, USPGPUB, USOCR, FPRS, JPO, EPO, DERWENT)	11/10/2006	π
EAST (USPAT, USPGPUB, USOCR, FPRS, JPO, EPO, DERWENT) Updating search	12/12/2006	π
Consulted with Cong Le	12/12/2006	тт
EAST (USPAT, USPGPUB, USOCR, FPRS, JPO, EPO, DERWENT) Updating search	8/30/2007	тт
EAST (USPAT, USPGPUB, USOCR, FPRS, JPO, EPO, DERWENT) Updating search	12/18/2007	π
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